

**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

YD/T 702-2018

Replacing YD/T 702-1993

Test methods of PIN-FET optical receive assembly

PIN FET光接收组件测试方法

(English Translation)

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What this standard covers

This standard specifies the terms and definitions, test methods, and reliability tests for PIN-FET light-receiving components. This standard applies to the testing of the photoelectric parameters of PIN-FET components.

Document data

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